

Dielectrics in Emerging Technologies -and- Persistent Phosphors

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K. Wörhoff
University of Twente
Enschede, The Netherlands

D. Misra
New Jersey Institute of Technology
Newark, New Jersey, USA

P. Mascher
McMaster University
Hamilton, Ontario, Canada

K. Sundaram
University of Central Florida
Orlando, Florida, USA

W. M. Yen
University of Georgia
Athens, Georgia, USA

J. Capobianco
Concordia University
Montreal, Quebec, Canada



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